



Docket No.: ASMEX.367A

Customer No. 20,995

### INFORMATION DISCLOSURE STATEMENT

Applicant : Michael A. Todd  
App. No. : 10/074,534  
Filed : February 11, 2002  
For : PROCESS FOR DEPOSITION OF  
SEMICONDUCTOR FILMS  
Examiner : Shrinivas H. Rao  
Group Art Unit : 2814

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Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Dear Sir:

Enclosed is form PTO-1449 listing references that are also enclosed.

This Information Disclosure Statement is being filed with an RCE or within three months of the filing date of this application and no fee is required in accordance with 37 C.F.R. § 1.97(b)(1), (b)(2), or (b)(4).

Respectfully submitted,

KNOBBE, MARTENS, OLSON & BEAR, LLP

Dated: 8/19/03

By: Joseph J. Mallon

Joseph J. Mallon  
Registration No. 39,287  
Attorney of Record  
Customer No. 20,995  
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|   |  |                                  |                               |
|---|--|----------------------------------|-------------------------------|
| FORM PTO-1449   | U.S. DEPARTMENT OF COMMERCE<br>PATENT AND TRADEMARK OFFICE | ATTY. DOCKET NO.<br>ASMEX.367A   | APPLICATION NO.<br>10/074,534 |
| <b>INFORMATION DISCLOSURE STATEMENT<br/>BY APPLICANT</b><br><br>(USE SEVERAL SHEETS IF NECESSARY) |  | APPLICANT<br>Michael A. Todd     |                               |
|   |  | FILING DATE<br>February 11, 2002 | GROUP<br>2814                 |

## U.S. PATENT DOCUMENTS

| EXAMINER<br>INITIAL | DOCUMENT NUMBER | DATE     | NAME           | CLASS | SUBCLASS | FILING DATE<br>(IF APPROPRIATE) |
|---------------------|-----------------|----------|----------------|-------|----------|---------------------------------|
| 1.                  | 5,214,002       | 05/25/93 | Hayashi et al. |       |          |                                 |
| 2.                  | 5,356,821       | 10/18/94 | Naruse et al.  |       |          |                                 |
| 3.                  | 5,471,330       | 11/28/95 | Sarma          |       |          |                                 |
| 4.                  | 6,103,600       | 08/15/00 | Ueda et al.    |       |          |                                 |
|                     |                 |          |                |       |          |                                 |

## FOREIGN PATENT DOCUMENTS

| EXAMINER<br>INITIAL | DOCUMENT NUMBER | DATE     | COUNTRY          | CLASS | SUBCLASS | TRANSLATION |    |
|---------------------|-----------------|----------|------------------|-------|----------|-------------|----|
|                     |                 |          |                  |       |          | YES         | NO |
| 5.                  | 11317530        | 16-11-99 | Japan (abstract) |       |          | X           |    |
| 6.                  | EP 0368651 A2   | 16-05-90 |                  |       |          |             |    |
| 7.                  | EP 0486047 A2   | 20-05-92 |                  |       |          |             |    |
| 8.                  | EP 0747974 A2   | 11-12-96 |                  |       |          |             |    |
| 9.                  | EP 1065728 A2   | 03-01-01 |                  |       |          |             |    |
| 10.                 | GB 2332564 A    | 23-06-99 | United Kingdom   |       |          |             |    |
|                     |                 |          |                  |       |          |             |    |

| EXAMINER<br>INITIAL | OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)  |
|---------------------|---|
| 11.                 | Olivares, J. et al.; "Solid-phase crystallization of amorphous SiGe films deposited by LPCVD on SiO <sub>2</sub> and glass," Thin Solid Films 337 (1999) pp. 51-54. |
|                     |   |

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|--|-----------------|
| EXAMINER   | DATE CONSIDERED |
| *EXAMINER: INITIAL IF CITATION CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP 609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED, INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT. |                 |